October 2006 FRFET $^{\text {TM }}$

## FQB9N50CF <br> 500V N-Channel MOSFET

## Features

- $9 \mathrm{~A}, 500 \mathrm{~V}, \mathrm{R}_{\mathrm{DS}(\text { on })}=0.85 \Omega @ \mathrm{~V}_{\mathrm{GS}}=10 \mathrm{~V}$
- Low gate charge ( typical 28nC)
- Low Crss ( typical 24pF)
- Fast switching
- $100 \%$ avalanche tested
- Improved dv/dt capability


## Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, electronic lamp ballasts based on half bridge topology.


## Absolute Maximum Ratings

| Symbol | Parameter |  |  | FQB9N50CF | Units |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {DSS }}$ | Drain-Source Voltage |  |  | 500 | V |
| ${ }^{\text {I }}$ | Drain Current | - Continuous ( $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ ) <br> - Continuous ( $\mathrm{T}_{\mathrm{C}}=100^{\circ} \mathrm{C}$ ) |  | 9 | A |
|  |  |  |  | 5.7 | A |
| $\mathrm{I}_{\mathrm{DM}}$ | Drain Current | - Pulsed | (Note 1) | 36 | A |
| $\mathrm{V}_{\text {GSS }}$ | Gate-Source Voltage |  |  | $\pm 30$ | V |
| $\mathrm{E}_{\text {AS }}$ | Single Pulsed Avalanche Energy |  | (Note 2) | 300 | mJ |
| ${ }_{\text {AR }}$ | Avalanche Current |  | (Note 1) | 5 | A |
| $\mathrm{E}_{\text {AR }}$ | Repetitive Avalanche Energy |  | (Note 1) | 9.6 | mJ |
| dv/dt | Peak Diode Recovery dv/dt |  | (Note 3) | 4.5 | V/ns |
| $\mathrm{P}_{\mathrm{D}}$ | Power Dissipation ( $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ ) |  |  | 173 | W |
|  | - Derate above $25^{\circ} \mathrm{C}$ |  |  | 1.38 | W/ ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{J},} \mathrm{T}_{\text {STG }}$ | Operating and Storage Temperature Range |  |  | -55 to +150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{L}}$ | Maximum lead temperature for soldering purposes, $1 / 8$ " from case for 5 seconds |  |  | 300 | ${ }^{\circ} \mathrm{C}$ |

## Thermal Characteristics

| Symbol | Parameter | FQB9N50CF | Units |
| :--- | :--- | :---: | :---: |
| $\mathrm{R}_{\theta \mathrm{JC}}$ | Thermal Resistance, Junction-to-Case | 0.72 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $\mathrm{R}_{\theta J \mathrm{~A}}$ | Thermal Resistance, Junction-to-Ambient ${ }^{*}$ | 40 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $\mathrm{R}_{\theta \mathrm{JA}}$ | Thermal Resistance, Junction-to-Ambient | 62.5 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |

[^0]
## Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
| :---: | :---: | :---: | :---: | :---: | :---: |
| FQB9N50CF | FQB9N50CFTM | D2-PAK | 330 mm | 24 mm | 800 |
| FQB9N50CFS | FQB9N50CFTM_WS | D2-PAK | 330 mm | 24 mm | 800 |

Electrical Characteristics $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Off Characteristics |  |  |  |  |  |  |
| BV ${ }_{\text {DSS }}$ | Drain-Source Breakdown Voltage | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=250 \mu \mathrm{~A}$ | 500 | -- | -- | V |
| $\begin{aligned} & \Delta \mathrm{BV}_{\mathrm{Dss}}{ }^{\prime} \\ & \Delta \mathrm{T}_{\mathrm{J}} \end{aligned}$ | Breakdown Voltage Temperature Coefficient | $\mathrm{I}_{\mathrm{D}}=250 \mu \mathrm{~A}$, Referenced to $25^{\circ} \mathrm{C}$ | -- | 0.57 | -- | V/ ${ }^{\circ} \mathrm{C}$ |
| IDSS | Zero Gate Voltage Drain Current | $\mathrm{V}_{\mathrm{DS}}=500 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}$ | -- | -- | 10 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{V}_{\mathrm{DS}}=400 \mathrm{~V}, \mathrm{~T}_{\mathrm{C}}=125^{\circ} \mathrm{C}$ | -- | -- | 100 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {GSSF }}$ | Gate-Body Leakage Current, Forward | $\mathrm{V}_{\mathrm{GS}}=30 \mathrm{~V}, \mathrm{~V}_{\mathrm{DS}}=0 \mathrm{~V}$ | -- | -- | 100 | nA |
| IGSSR | Gate-Body Leakage Current, Reverse | $V_{G S}=-30 \mathrm{~V}, \mathrm{~V}_{\mathrm{DS}}=0 \mathrm{~V}$ | -- | -- | -100 | nA |
| On Characteristics |  |  |  |  |  |  |
| $\mathrm{V}_{\mathrm{GS} \text { (th) }}$ | Gate Threshold Voltage | $\mathrm{V}_{\mathrm{DS}}=\mathrm{V}_{\mathrm{GS}}, \mathrm{I}_{\mathrm{D}}=250 \mu \mathrm{~A}$ | 2.0 | -- | 4.0 | V |
| $\mathrm{R}_{\mathrm{DS} \text { (on) }}$ | Static Drain-Source On-Resistance | $\mathrm{V}_{G S}=10 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=4.5 \mathrm{~A}$ | -- | 0.7 | 0.85 | $\Omega$ |
| $\mathrm{g}_{\mathrm{FS}}$ | Forward Transconductance | $\mathrm{V}_{\mathrm{DS}}=40 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=4.5 \mathrm{~A} \quad$ (Note 4) | -- | 6.5 | -- | S |
| Dynamic Characteristics |  |  |  |  |  |  |
| $\mathrm{C}_{\text {iss }}$ | Input Capacitance | $\begin{aligned} & \mathrm{V}_{\mathrm{DS}}=25 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}, \\ & \mathrm{f}=1.0 \mathrm{MHz} \end{aligned}$ | -- | 790 | 1030 | pF |
| $\mathrm{C}_{\text {oss }}$ | Output Capacitance |  | -- | 130 | 170 | pF |
| $\mathrm{C}_{\text {rss }}$ | Reverse Transfer Capacitance |  | -- | 24 | 30 | pF |
| Switching Characteristics |  |  |  |  |  |  |
| $\mathrm{t}_{\mathrm{d} \text { (on) }}$ | Turn-On Delay Time | $\begin{aligned} & \mathrm{V}_{\mathrm{DD}}=250 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=9 \mathrm{~A}, \\ & \mathrm{R}_{\mathrm{G}}=25 \Omega \end{aligned}$ <br> (Note 4, 5) | -- | 18 | 45 | ns |
| $\mathrm{t}_{\mathrm{r}}$ | Turn-On Rise Time |  | -- | 65 | 140 | ns |
| $\mathrm{t}_{\text {d(off) }}$ | Turn-Off Delay Time |  | -- | 93 | 195 | ns |
| $\mathrm{t}_{\mathrm{f}}$ | Turn-Off Fall Time |  | -- | 64 | 125 | ns |
| $\mathrm{Q}_{\mathrm{g}}$ | Total Gate Charge | $\begin{aligned} & \mathrm{V}_{\mathrm{DS}}=400 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=9 \mathrm{~A}, \\ & \mathrm{~V}_{\mathrm{GS}}=10 \mathrm{~V} \end{aligned}$ <br> (Note 4, 5) | -- | 28 | 35 | nC |
| $\mathrm{Q}_{\mathrm{gs}}$ | Gate-Source Charge |  | -- | 4 | -- | nC |
| $\mathrm{Q}_{\mathrm{gd}}$ | Gate-Drain Charge |  | -- | 15 | -- | nC |
| Drain-Source Diode Characteristics and Maximum Ratings |  |  |  |  |  |  |
| Is | Maximum Continuous Drain-Source Diode Forward Current |  | -- | -- | 9 | A |
| $\mathrm{I}_{\text {SM }}$ | Maximum Pulsed Drain-Source Diode Forward Current |  | -- | -- | 36 | A |
| $\mathrm{V}_{\text {SD }}$ | Drain-Source Diode Forward Voltage | $V_{G S}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{S}}=9 \mathrm{~A}$ | -- | -- | 1.4 | V |
| $\mathrm{t}_{\text {rr }}$ | Reverse Recovery Time | $\begin{aligned} & \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{S}}=9 \mathrm{~A}, \\ & \mathrm{~d}_{\mathrm{F}} / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s} \end{aligned}$ <br> (Note 4) | -- | 100 | -- | ns |
| $\mathrm{Q}_{\mathrm{rr}}$ | Reverse Recovery Charge |  | -- | 300 | -- | nC |

NOTES:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. $L=8 \mathrm{mH}, \mathrm{I}_{A S}=9 \mathrm{~A}, \mathrm{~V}_{\mathrm{DD}}=50 \mathrm{~V}, R_{G}=25 \Omega$, Starting $T_{J}=25^{\circ} \mathrm{C}$
3. $\mathrm{I}_{\mathrm{SD}} \leq 9 \mathrm{~A}, \mathrm{di} / \mathrm{dt} \leq 200 \mathrm{~A} / \mu \mathrm{s}, \mathrm{V}_{\mathrm{DD}} \leq \mathrm{BV}_{\mathrm{DSs}}$, Starting $\mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$
4. Pulse Test : Pulse width $\leq 300 \mu \mathrm{~s}$, Duty cycle $\leq 2 \%$
5. Essentially independent of operating temperature

## Typical Performance Characteristics

Figure 1. On-Region Characteristics


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage


Figure 5. Capacitance Characteristics


Figure 2. Transfer Characteristics


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue


Figure 6. Gate Charge Characteristics


## Typical Performance Characteristics (continued)

Figure 7. Breakdown Voltage Variation vs. Temperature


Figure 9. Maximum Safe Operating Area


Figure 8. On-Resistance Variation vs. Temperature


Figure 10. Maximum Drain Current vs. Case Temperature


Figure 11. Transient Thermal Response Curve


## Gate Charge Test Circuit \& Waveform



Resistive Switching Test Circuit \& Waveforms


Unclamped Inductive Switching Test Circuit \& Waveforms


## Peak Diode Recovery dv/dt Test Circuit \& Waveforms



Body Diode Reverse Current
$V_{D s}$ (DUT)



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FQB9N50CF
500V N－Channel MOSFET

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## General description

These N－Channel enhancement mode power field effect transistors are produced using Fairchild＇s proprietary，planar stripe，DMOS technology．

This advanced technology has been especially tailored to minimize on－state resistance，provide superior switching performance，and withstand high energy pulse in the avalanche and commutation mode．These devices are well suited for high efficiency switched mode power supplies，electronic lamp ballasts based on half bridge topology．
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## Features

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| Product | Product status | Pb－free Status | Pricing＊ | Package type | Leads | Packing method | Package Marking Convention＊＊ |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |


| FQB9N50CFTM | Full Production |  | \$1.40 | TO-263(D2PAK) | 2 | TAPE REEL | Line 1: \$Y (Fairchild logo) \&Z (Asm. Plant Code) \&E\&3 (3-Digit Date Code) Line 2: FQB Line 3: 9N50CF |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |

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[^0]:    When mounted on the minimum pad size recommended (PCB Mount)

